

Search Notes 	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10508906	ADACHI, TATSUYA
	Examiner Trujillo, James K	Art Unit 2116

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
EAST (USPAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB), see attached; NPL: IEEE; Inventor Search/DP; Text search in cls 713/300+.	3/21/07	JKT

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner